

<b>Notice of References Cited</b>	Application/Control No. 10/002,915	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner BRIAN P. YENKE	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,266,092	07-2001	Wang et al.	348/448
*	B	US-6,754,371	06-2004	Kondo et al.	382/107
*	C	US-6,636,267	10-2003	Adachi, Hajime	348/448
*	D	US-6,633,612	10-2003	Selby, Steve	375/240.16
*	E	US-6,630,961	10-2003	Shin et al.	348/448
*	F	US-6,621,936	09-2003	Kondo et al.	382/260
*	G	US-6,512,550	01-2003	de Garrido et al.	348/452
*	H	US-6,452,972	09-2002	Ohara, Kazuhiro	375/240.12
*	I	US-6,348,949	02-2002	McVeigh, Jeffrey S.	348/452
*	J	US-6,307,560	10-2001	Kondo et al.	345/619
*	K	US-6,295,091	09-2001	Huang, Samson	348/448
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.